

## Octal-Bus Transceiver/Registers, 3-State

B3 DATA CD54/74AC/ACT651 - Inverting
B5 PORT CD54/74AC/ACT652 - Non-Inverting

#### **Type Features:**

- Buffered inputs
- Typical propagation delay: 5.3 ns @ V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C, C<sub>L</sub> = 50 pF

**FUNCTIONAL DIAGRAM** 

92CS-42677

The RCA CD54/74AC651 and CD54/74AC652 and the CD54/74ACT651 and CD54/74ACT652 3-state, octal-bus transceiver/registers use the RCA ADVANCED CMOS technology. The CD54/74AC651 and CD54/74ACT651 have inverting outputs. The CD54/74AC652 and CD54/74ACT652 have non-inverting outputs. These devices consist of bus transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Output Enables OEAB and OEBA are provided to control the transceiver functions. SAB and SBA control pins are provided to select whether real-time or stored data is transferred. The circuitry used for select control will eliminate the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. A LOW input level selects real-time data, and a HIGH selects stored data. The following examples demonstrate the four fundamental busmanagement functions that can be performed with the octal-bus transceivers and registers.

Data on the A or B data bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock pins (CAB or CBA) regardless of the select or enable control pins. When SAB and SBA are in the real-time transfer mode, it is also possible to store data without using the internal D-type flip-flops by simultaneously enabling  $OE_{AB}$  and  $\overline{OE}_{BA}$ . In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines will remain at its last state.

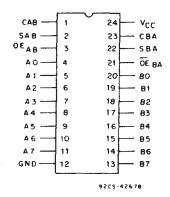
The CD74AC/ACT651 and CD74AC/ACT652 are supplied in 24-lead dual-in-line narrow-body plastic packages (EN suffix) and in 24-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Commercial (0 to 70°C); Industrial (-40 to +85°C); and Extended Industrial/Military (-55 to +125°C).

The CD54AC/ACT651 and CD54AC/ACT652, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

#### **Family Features:**

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST\*/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply
- ± 24-mA output drive current
  - Fanout to 15 FAST\* ICs
  - Drives 50-ohm transmission lines

<sup>\*</sup>FAST is a Registered Trademark of Fairchild Semiconductor Corp.



**TERMINAL ASSIGNMENT** 

This data sheet is applicable to the CD74AC562, CD74ACT651, and CD74ACT652. The CD54/74AC651, CD54AC652, CD54ACT651 and CD54ACT652 were not acquired from Harris Semiconductor.

File Number 1974

#### **FUNCTION TABLE**

		INP	UTS			DAT	A I/O	OPERATION (	OR FUNCTION	
OEAB	OEBA	CAB	CBA	SAB	SBA	A0 THRU A7	B0 THRU B7	651	652	
L	Н	HorL	H or L	×	X	Input	lanut	Isolation *	Isolation*	
L	Н	_/_		Х	Х	Input	Input	Store A and B Data	Store A and B Data	
X	Н		HorL	, х	Χ	Input	Unspecified <sup>†</sup>	Store A, Hold B	Store A, Hold B	
Н	<u>H</u>			x‡	Х	Input	Output	Store A in both registers	Store A in both registers	
L	X	HorL		×	Х	Unspecified†	Input	Hold A, Store B	Hold, A Store B	
L	L			X	X‡	Output	Input	Store B in both registers	Store B in both registers	
L	L	х	X	X	L	0.44		Real-Time B Data to A Bus	Real-Time B Data to A Bus	
L	L	Х	HorL	X	Н	Output	Input	Stored B Data to A Bus	Stored B Data to A Bus	
Н	Н	X	Х	L	X			Real-Time A Data to B Bus	Real-Time A Data to B Bus	
Н	Н	HorL	Х	Н	Х	Input	Output	Stored A Data to B Bus	Stored A Data to B Bus	
н	-	HorL	Harl	н	н	0.4	Stored A Data to B Bus an		Stored A Data to B Bus	
L		TIOIL	HULL	П	П	Output	Output	Stored B Data to A bus	Stored B Data to A Bus	

<sup>\*</sup> To prevent excess currents in the High-Z (isolation) modes, all I/O terminals should be terminated with  $10k\Omega$  to  $1M\Omega$  resistors.

#### MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE (Vcc) -0.5 to 6 V	,
DC INPUT DIODE CURRENT, $I_{ik}$ (for $V_i < -0.5 \text{ V}$ or $V_i > V_{CC} + 0.5 \text{ V}$ )	
DC OUTPUT DIODE CURRENT, $I_{OK}$ (for $V_O < -0.5$ V or $V_O > V_{CC} + 0.5$ V)	
DC OUTPUT SOURCE OR SINK CURRENT per Output Pin, $I_0$ (for $V_0 > -0.5$ V or $V_0 < V_{cc} + 0.5$ V)	
DC V <sub>CC</sub> or GROUND CURRENT (I <sub>CC</sub> or I <sub>GND</sub> )	
POWER DISSIPATION PER PACKAGE (Po):	
For T <sub>A</sub> = -55 to +100°C (PACKAGE TYPE E)	,
For T <sub>A</sub> = +100 to +125°C (PACKAGE TYPE E)	1
For T <sub>A</sub> = -55 to +70°C (PACKAGE TYPE M)	1
For T <sub>A</sub> = +70 to +125°C (PACKAGE TYPE M)	•
OPERATING-TEMPERATURE RANGE (T <sub>a</sub> )55 to +125°C	
STORAGE TEMPERATURE (T <sub>stq</sub> )65 to ±150°C	
LEAD TEMPERATURE (DURING SOLDERING):	
At distance 1/16 $\pm$ 1/32 in. (1.59 $\pm$ 0.79 mm) from case for 10 s maximum	
Unit inserted into PC board min. thickness 1/16 in. (1.59 mm) with solder contacting lead tips only +300°C	
*For up to 4 outputs per device; add + 25 mA for each additional output	

#### **RECOMMENDED OPERATING CONDITIONS:**

For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTICS	LIA	LINUTO		
CHARACTERISTICS	MIN.	1.5 5.5 4.5 5.5 0 V <sub>cc</sub> -55 +125	UNITS	
Supply-Voltage Range, Vcc*:				
(For T <sub>A</sub> = Full Package-Temperature Range)		İ		
AC Types	1.5	5.5	V	
ACT Types	4.5	5.5	V	
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub>	0	Vcc	V	
Operating Temperature, T <sub>A</sub>	-55	+125	°C	
Input Rise and Fall Slew Rate, dt/dv		† <del></del>		
at 1.5 V to 3 V (AC Types)	0	50	ns/V	
at 3.6 V to 5.5 V (AC Types)	0	20	ns/V	
at 4.5 V to 5.5 V (ACT Types)	0	10	ns/V	

<sup>\*</sup>Unless otherwise specified, all voltages are referenced to ground.

<sup>†</sup> The data output functions may be enabled or disabled by various signals at the OE<sub>AB</sub> or OE<sub>BA</sub> inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every low-to-high transition on the clock inputs.

 <sup>\$</sup>Select control = L: clocks can occur simultaneously.
 \$Select control = H: clocks must be staggered in order to load both registers.

STATIC ELECTRICAL CHARACTERISTICS: AC Series

. •						AMBIEN	TEMPE	RATURE	(T <sub>A</sub> ) - °	С .		
CHARACTERIST	ICS	TEST CO	NDITIONS	V <sub>cc</sub>	+:	25	-40't	o +85	-55 to	+125	UNITS	
		V, (V).	l <sub>o</sub> (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
High-Level Input Voltage	VIH			1.5 3 5.5	1.2 2.1 3.85		1.2 2.1 3.85		1.2 2.1 3.85		v	
Low-Level Input Voltage	Vil			1.5 3 5.5		0.3 0.9 1.65	_	0.3 0.9 1.65	=	0.3 0.9 1.65	V	
High-Level Output			-0.05	1.5	1.4		1.4	_	1.4			
Voltage	V <sub>OH</sub>	VIH	-0.05	3	2.9	<u> </u>	2.9	_	2.9		]	
,		or	-0.05	4.5	4.4	_	4.4	_	4.4			
		V <sub>iL</sub>	-4	3	2.58		2.48	_	2.4		) v	
			-24	4.5	3.94	_	3.8	_	3.7			
		#, * }	-75	5.5	_		3.85				]	
		"' (	-50	5.5		_			3.85		<u></u>	
Low-Level Output			0.05	1.5		0.1		0.1		0.1		
Voltage	V <sub>OL</sub>	VOL	V <sub>IH</sub>	0.05	3		0.1		0.1	-	0.1	
		or	0.05	4.5		0.1		0.1		0.1		
		VıL	12	3		0.36		0.44		0.5	) v	
	!		24	4.5		0.36		0.44		0.5		
		#, * {	75	5.5				1.65			]	
		(	50	5.5	_		<u> </u>			1.65		
Input Leakage Current	l <sub>t</sub>	V <sub>cc</sub> or GND		5.5	_	±0.1		±1	_	±1	μΑ	
3-State Leakage Current	łoz	VIH or VIL Vo= Vcc or GND		5.5		±0.5		±5		±10	μΑ	
Quiescent Supply Current, MSI	Icc	V <sub>cc</sub> or GND	0	5.5	_	8		80		160	μΑ	

<sup>#</sup>Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

<sup>\*</sup>Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

#### STATIC ELECTRICAL CHARACTERISTICS: ACT Series

					AMBIEN	T TEMPE	RATURE	(T <sub>A</sub> ) - °	С		
CHARACTERISTI	CS	TEST COM	NDITIONS	V <sub>cc</sub>	+	25	-40 t	o +85	-55 to	+125	UNITS
		V, (V)	l <sub>o</sub> (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
High-Level Input Voltage	V <sub>IH</sub>			4.5 to 5.5	2	_	2	· —	2		v
Low-Level Input Voltage	ViL		•	4.5 to 5.5		0.8		0.8	_	0.8	v
High-Level Output		V <sub>IH</sub>	-0.05	4.5	4.4	_	4.4		4.4	<u> </u>	
Voltage	V <sub>OH</sub>	or V <sub>IL</sub>	-24	4.5	3.94		3.8		3.7		]
		#, * {	-75	5.5			3.85	-		[	V
		"' ℓ	-50	5.5				_	3.85	_	
Low-Level Output		V <sub>IH</sub>	0.05	4.5	–	0.1	-	0.1	-	0.1	
Voltage	Vol	or V <sub>IL</sub>	24	4.5	<u> </u>	0.36	_	0.44		0.5	1 v
		#, * {	75	5.5	_	_	_	1.65	_	_	1
		<b>"</b> '	50	5.5	_				_	1.65	1
Input Leakage Current	ŀı	V <sub>∞</sub> or GND		5.5	_	±0.1	_	±1	_	±1	μΑ
3-State Leakage Current	loz	VIH or VIL Vo= Vcc or GND		5.5	_	±0.5	_	±5	_	±10	μΑ
Quiescent Supply Current, MSI	lcc	V <sub>cc</sub> or GND	0	5.5	_	8	_	80	_	160	μΑ
Additional Quiescent S Current per Input Pi TTL Inputs High 1 Unit Load		V <sub>cc</sub> -2.1		4.5 to 5.5		2.4	_	2.8		3	mA

<sup>#</sup>Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.
\*Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

#### **ACT INPUT LOADING TABLE**

INPUT	UNIT LOAD*
CAB, CBA	1.25
SAB, SBA	1.2
OE <sub>AB</sub>	0.67
OE <sub>BA</sub>	1.17
An, Bn	0.4

\*Unit load is ΔI<sub>CC</sub> limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25°C.

PREREQUISITE FOR SWITCHING: AC Series

		V <sub>cc</sub> (V)	AMBI	ENT TEMPE	RATURE (1	(A) - °C	
CHARACTERISTICS	SYMBOL		-40 1	o +85	-55 to	UNITS	
			MIN.	MAX.	MIN.	MAX.	].
Max. Frequency	fmax	1.5 3.3* 5†	11 101 143		10 89 125	_ _ _	MHz
Setup Time Data to Clock	tsu	1.5 3.3 5	27 3.1 2.2	=	31 3.5 2.5		ns
Hold Time Data to Clock	t <sub>H</sub>	1.5 3.3 5	2 2	=	2 2 2		ns
Clock Pulse Data to Clock	tw	1.5 3.3 5	44 4.9 3.5	=	50 5.6 4		ns

\*3.3 V: min. is @ 3 V †5 V; min. is @ 4.5 V

SWITCHING CHARACTERISTICS: AC Series; t., t. = 3 ns, CL = 50 pF

			AMBI	ENT TEMPE	RATURE (	Γ <sub>Λ</sub> ) - °C	
CHARACTERISTICS	SYMBOL	V <sub>cc</sub>	-40	to +85	-55 t	o +125	UNITS
O MAIN TERMOTION	01002	(V)	MIN.	MAX.	MIN.	MAX.	7
Propagation Delays: Store A Data to B Bus Store B Data to A Bus 652 Store A Data to B Bus Store B Data to A Bus 651	tры tры tры tры	1.5 3.3* 5† 1.5 3.3 5	4.8 3.5 4.8 3.5	154 17.1 12.3 154 17.1 12.3	4.7 3.4 - 4.7 3.4	169 18.9 13.5 169 18.9 13.5	ns
A Data to B Bus B Data to A Bus 652	t <sub>PLH</sub> t <sub>PHL</sub>	1.5 3.3 5	4 2.8	125 14 10	3.9 2.8	138 15.4 11	ns
A Data to B Bus B Data to A Bus 651	telh tehl	1.5 3.3 5	- 4 2.8	125 14 10	3.9 2.8	138 15.4 11	ns
Select to Data 652	telm tem	1.5 3.3 5	4.3 3.1	136 15.3 10.9	4.2 3	150 16.8 12	ns
Select to Data 651	tplH tpHL	1.5 3.3 5	4.3 3.1	136 15.3 10.9	4.2 3	150 16.8 12	ns
3-State Enabling/ Disabling Time Bus to Output or Register to Output	tezl tezh telz tenz	1.5 3.3 5	5.2 3.5	154 18.4 12.3	5.1 3.4	169 20.2 13.5	ns
Power Dissipation Capacitance	CPD§	_	150	Тур.	150	Тур.	pF
Min. (Valley)  During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>OHV</sub> V <sub>OHV</sub> See Fig. 1	5		V			
Max. (Peak) During Switching of Other Outputs (Output Under Test Not Switching)	Vol.P See Fig. 1	5	1 Typ. @ 25°C				٧
Input Capacitance	C <sub>1</sub>			10		10	pF
3-State Output Capacitance	Co	_		15		15	pF

\*3 3 V: min, is @ 3.6 V max. is @ 3 V

†5 V: min. is @ 5.5 V max. is @ 4.5 V  $C_{PD}$  is used to determine the dynamic power consumption, per package.  $P_D = V_{CC}^2 C_{PD} f_i + \Sigma (V_{CC}^2 C_L f_o)$  where  $f_i =$  input frequency

f<sub>o</sub> = output frequency C<sub>L</sub> = output load capacitance

Vcc - supply voltage.

#### PREREQUISITE FOR SWITCHING: ACT Series

		V <sub>cc</sub> (V)	AMBI				
CHARACTERISTICS	SYMBOL		-40 t	o +85	-55 to	UNITS	
		(*)	MIN.	MAX.	MIN.	MAX.	
Max. Frequency	f <sub>max</sub>	5*	125	_	110	_	MHz
Setup Time Data to Clock	tsu	5	2.2		2.5	_	ns
Hold Time Data to Clock	t <sub>H</sub>	5	2	-	2	_	ns
Clock Pulse Width	tw	5	3.9	_	4.5	_	ns

<sup>\*5</sup> V: min. is @ 4.5 V

### SWITCHING CHARACTERISTICS: ACT Series; $t_{\rm r},\,t_{\rm f}$ = 3 ns, $C_{\rm L}$ = 50 pF

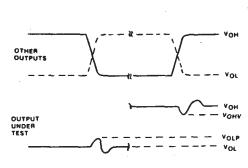
			AMBI	ENT TEMP	ERATURE (	T <sub>A</sub> ) - °C	
CHARACTERISTICS	SYMBOL	V <sub>cc</sub>	-40	to +85	-55 t	o +125	UNITS
· · · · · · · · · · · · · · · · · · ·		(V)	MIN.	MAX.	MIN.	MAX.	
Propagation Delays: Store A Data to B Bus Store B Data to A Bus 652	t <sub>PLH</sub> t <sub>PHL</sub>	5⁺	4	14.1	3.9	15.5	ns
Store A Data to B Bus Store B Data to A Bus 651	t <sub>PLH</sub> t <sub>PHL</sub>	5	4	14.1	3.9	15.5	ns
A Data to B Bus B Data to A Bus 652	t <sub>PLH</sub> t <sub>PHL</sub>	5	3.2	11.4	3.1	12.5	ns
Ā Data to B Bus B Data to A Bus 651	ŧрын tрны	5	3.2	11.4	3.1	12.5	ns
Select to Data 652	t <sub>PLH</sub> t <sub>PHL</sub>	5	3.7	13.2	3.6	14.5	ns
Select to Data 651	t <sub>PEH</sub>	5	4	14.1	3.9	15.5	ns
3-State Enabling/ Disabling Time Bus to Output or Register to Output	tezi. tezh telz tenz	5	4	14.1	3.9	15.5	ns
Power Dissipation Capacitance	C <sub>PO</sub> §	_	150	Тур.	150 Typ.		pF
Min. (Valley)  During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>OHV</sub> V <sub>OHV</sub> See Fig. 1	5	4 Typ. @ 25°C				v
Max. (Peak) During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>OLP</sub> See Fig. 1	5	1 Typ. @ 25°C				٧
Input Capacitance	Cı	-		10	_	10	ρF
3-State Output Capacitance	Co	_		15	_	15	pF

<sup>\*5</sup> V: min. is @ 5.5 V max. is @ 4.5 V

§C<sub>PD</sub> is used to determine the dynamic power consumption, per package.  $P_D = V_{CC}^2 C_{PD} f_i + \sum V_{CC}^2 C_L f_0 + V_{CC} \Delta I_{CC}$  where  $f_i = input frequency$ 

fo = output frequency

C<sub>L</sub> = output load capacitance V<sub>cc</sub> = supply voltage.



- 1. VOHY AND VOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.

  2. INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS: PRR © 1 MHZ, \$\frac{1}{2}\$ on \$\frac{1}{2}\$ of \$\scrt{2}\$ of \$\scr
- IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 JF CAPACITOR. SCOPE AND PROBES REQUIRE 700-MHz BANDWIDTH.

9205-42406

Fig. 1 - Simultaneous switching transient waveforms.

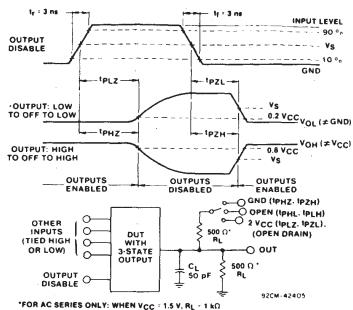


Fig. 2 - Three-state propagation delay waveforms and test circuit.

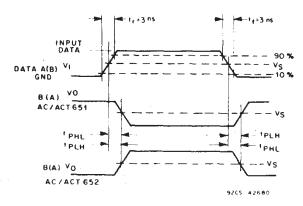


Fig. 3 - Propagation delay times.

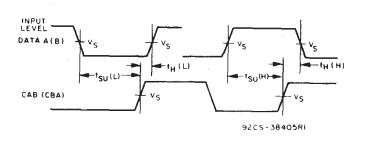


Fig. 4 - Data setup and hold times.

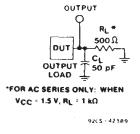


Fig. 5 - Test circuit.

	CD54/74AC	CD54/74ACT
Input Level	V <sub>cc</sub>	3 V
Input Switching Voltage, Vs	0.5 V <sub>cc</sub>	1.5 V
Output Switching Voltage, Vs	0.5 V <sub>cc</sub>	0.5 V <sub>cc</sub>

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
CD74AC652M	Obsolete	Production	SOIC (DW)   24	-	-	Call TI	Call TI	-55 to 125	AC652M
CD74AC652M96	Active	Production	SOIC (DW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC652M
CD74AC652M96.A	Active	Production	SOIC (DW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC652M
CD74ACT652M	Obsolete	Production	SOIC (DW)   24	-	-	Call TI	Call TI	-55 to 125	ACT652M
CD74ACT652M96	Active	Production	SOIC (DW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT652M
CD74ACT652M96.A	Active	Production	SOIC (DW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT652M

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



## **PACKAGE OPTION ADDENDUM**

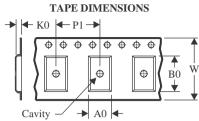
www.ti.com 11-Nov-2025

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 16-Apr-2024

#### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74AC652M96	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1
CD74ACT652M96	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 16-Apr-2024



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74AC652M96	SOIC	DW	24	2000	350.0	350.0	43.0
CD74ACT652M96	SOIC	DW	24	2000	350.0	350.0	43.0

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